

IDS 12/12/03

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2461		SERIAL NO. <i>10/734,899</i> PRIORITY 10/220,887	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Eugene Marsh et al.			
				FILING DATE PRIORITY August 27, 2002		GROUP PRIORITY 2822	
U.S. PATENT DOCUMENTS							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
<i>MBD</i>	AA	5,925,411	07/1999	van de Ven et al.	427	248.1	
	AB	6,270,572 B1	08/2001	Kim et al.	117	93	
	AC	6,301,434 B1	10/2001	McDiarmid et al.	392	416	
	AD	6,305,314 B1	10/2001	Sneh et al.	118	723	
	AE	6,355,561 B1	03/2002	Sandhu et al.	438	676	
	AF	6,403,156 B2	06/2002	Jang et al.	427	255.34	
	AG	6,426,307 B2	07/2002	Lim	438	778	
	AH	6,468,924 B2	10/2002	Lee et al.	438	763	
<i>V</i>	AI	6,475,286 B1	11/2002	Frijlink	118	719	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AJ						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER		DATE CONSIDERED <i>2/15/2005</i>					
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Eugene Marsh et al.			
				FILING DATE PRIORITY August 27, 2002		GROUP PRIORITY 2822	
U.S. PATENT DOCUMENTS							
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,482,262 B1	11/2002	Elers et al.	117	84	
	AB	6,534,395 B2	03/2003	Werkhoven et al.	438	627	
	AC	6,585,823 B1	07/2003	Van Wijck	117	89	
	AD	6,586,343 B1	07/2003	Ho et al.	438	758	
	AE	20010024387	09/2001	Raaijmakers et al.	365	200	
	AF	20010041250	11/2001	Werkhoven et al.	428	212	
	AG	20010050039 A1	12/2001	Park	117	102	
	AH	20010054381 A1	12/2001	Umotoy et al.	118	715	
	AI	6,613,587 B1	09/2003	Carpenter et al.	345	473	
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2461	SERIAL NO. PRIORITY 10/229,887
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Eugene Marsh et al.	
				FILING DATE PRIORITY August 27, 2002	GROUP PRIORITY 2822

U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
KBP	AA	10/132,003		Dando et al. (as filed)			04/24/02
	AB	10/132,767		Dando et al. (as filed)			04/24/02
	AC	10/150,388		Mardian et al. (as filed)			05/17/02
	AD	6,620,253 B1	09/2003	Dando et al.	369	124.07	
	AE	10/163,689		Derderian et al. (as filed)			06/05/02
	AF	10/208,314		Castroville et al. (as filed)			07/29/02
	AG	10/222,282		Sarigiannis et al. (as filed and amended)			08/15/02
	AH	10/222,304		Sarigiannis et al. (as filed)			08/15/02
V	AI						

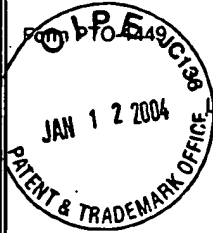
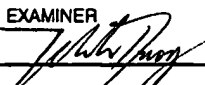
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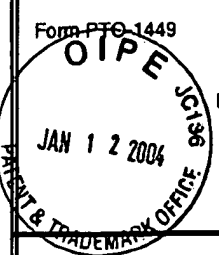
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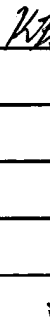
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Micron Technology, Inc.			
				FILING DATE December 12, 2003		GROUP Unknown <i>2822</i>	
U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>WED</i> ↓	AA	5,879,459	03/1999	Gadgil et al.	118	715	
	AB	5,972,430	10/1999	DiMeo, Jr. et al.	427	255.32	
	AC	6,174,377 B1	01/2001	Doering et al.	118	729	
	AD	6,200,893 B1	03/2001	Sneh	438	685	
	AE	6,287,965 B1	09/2001	Kang et al.	438	648	
	AF	6,387,185 B2	05/2002	Doering et al.	118	729	
	AG	6,391,785 B1	05/2002	Satta et al.	438	704	
	AH	6,451,119 B2	09/2002	Sneh et al.	118	715	
↓	AI	6,451,695 B2	09/2002	Sneh	438	685	
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Document Number	Date	Country	Class	Subclass	Translation		
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<i>WED</i> ↓	AJ	01/27347 A1	04/2001	WO	16	44	
	AK	01/29280 A1	04/2001	WO	16	32	
	AL	01/29893 A1	04/2001	WO	21	768	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
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AN							
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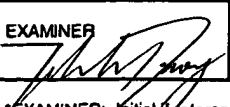
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						FILING DATE December 12, 2003		GROUP Unknown	
U.S. PATENT DOCUMENTS									
Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate		
<i>KBD</i> ↓		6,475,276 B1	11/2002	Elers et al.	117	84			
	AB	6,475,910 B1	11/2002	Sneh	438	685			
	AC	6,589,886 B2	07/2003	Kim et al.	438	758			
	AD	6,590,251 B2	07/2003	Kang et al.	257	310			
	AE	6,602,784 B2	08/2003	Sneh	438	680			
	AF	6,630,401 B2	10/2003	Sneh	438	680			
	AG	6,638,862 B2	10/2003	Sneh	438	685			
	AH	6,664,192 B2	12/2003	Satta et al.	438	704			
	AI	2002/0086111 A1	07/2002	Byun et al.	427	255.394			
FOREIGN PATENT DOCUMENTS									
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<i>KBD</i>	AJ	01/66832 A2	09/2001	WO	25	14			
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Form PTO 1449 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2461		SERIAL NO. 10/734,999	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Micron Technology, Inc.			
FILING DATE December 12, 2003				GROUP Unknown			

U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	AA	2002/0108714 A1	08/2002	Doering et al.	156	345.51	
	AB	2002/0187256 A1	12/2002	Elers et al.	427	99	
	AC	2003/0031807 A1	02/2003	Elers et al.	427	569	
	AD	2003/0032281 A1	02/2003	Werkhoven et al.	438	640	
	AE	2003/0129826 A1	07/2003	Werkhoven et al.	438	627	
	AF	2003/0183171 A1	10/2003	Sneh et al.	118	724	
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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				FILING DATE December 12, 2003		GROUP 1702 2822	

U.S. PATENT DOCUMENTS							
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KBD V	AA	6,015,597	01/2000	David	427	577	
	AB	6,197,120	03/2001	David	118	716	
	AC	6,482,476	11/2002	Liu	427	535	
	AD	6,620,723	09/2003	Byun	438	627	
	AE	6,696,157	02/2004	David	428	408	
	AF	6,696,368	02/2004	Derraa et al.	438	761	
	AG	6,720,027	04/2004	Yang et al.	427	123	
	AH	6,727,169	04/2004	Raaijmakers et al.	438	622	
	AI	6,746,952	06/2004	Derraa et al.	438	627	

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
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KBD WO 04/011693 A1	02/2004	WIPO (Micron Technology, Inc.)	16	44			
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EXAMINER <i>[Signature]</i>	DATE CONSIDERED 2/15/2005
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Micron Technology, Inc.			
					FILING DATE December 12, 2003		GROUP 1762	
U.S. PATENT DOCUMENTS								
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	AA	6,753,271 B2	06/2004	Sarigiannis et al.	438	785		
	AB	2003/0143328 A1	07/2003	Chen et al.	427	255.28		
	AC	2003/0085424 A1	05/2003	Bryant et al.	257	347		
	AD	2004/0137728 A1	07/2004	Gallagher et al.	438	689		
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